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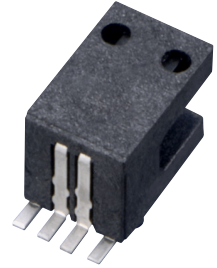
[GP1S25J0000F](#)

For any questions, you can email us directly:

sales@integrated-circuit.com

GP1S25J0000F

SMT, Gap : 1.6mm, Slit : 0.3mm
 Phototransistor Output,
 Compact Transmissive
 Photointerrupter



■ Description

GP1S25J0000F is a compact-package, phototransistor output, transmissive photointerrupter, with opposing emitter and detector in a molding that provides non-contact sensing. The compact package series is a result of unique technology combining transfer and injection molding.

This device has two positioning pins, right angle package, and is reflow solderable.

■ Features

1. Transmissive with phototransistor output
2. Highlights:
 - Compact Size
 - Positioning Pin
 - Surface Mount Type (SMT)
 - Sideling terminal
3. Key Parameters:
 - Gap Width: 1.6mm
 - Slit Width (detector side): 0.3mm
 - Package: 3.85×3.4×5.2mm
4. Lead free and RoHS directive compliant

■ Agency approvals/Compliance

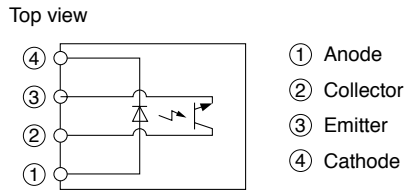
1. Compliant with RoHS directive

■ Applications

1. General purpose detection of object presence or motion.
2. Example: printer, lens control for camera

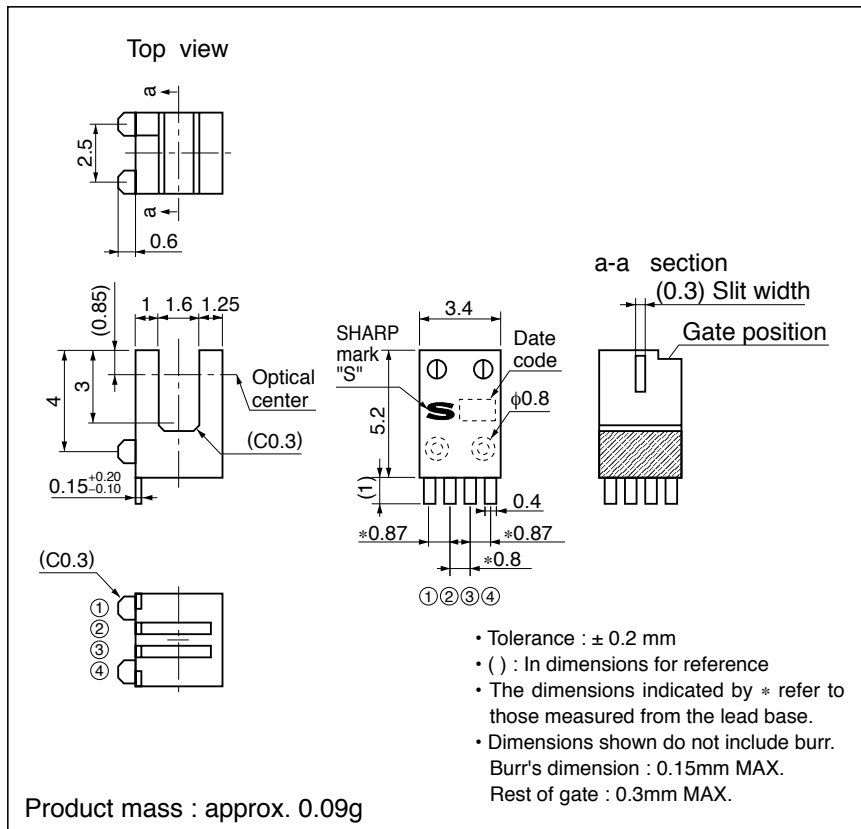
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■ Internal Connection Diagram



■ Outline Dimensions

(Unit : mm)



Plating material : SnCu (Cu : TYP. 2%)

Date code (2 digit)

1st digit		2nd digit	
Year of production		Month of production	
A.D.	Mark	Month	Mark
2000	0	1	1
2001	1	2	2
2002	2	3	3
2003	3	4	4
2004	4	5	5
2005	5	6	6
2006	6	7	7
2007	7	8	8
2008	8	9	9
2009	9	10	X
2010	0	11	Y
:	:	12	Z

repeats in a 10 year cycle

Rank mark

There is no rank indicator.

Country of origin

Japan

■ Absolute Maximum Ratings ($T_a=25^\circ\text{C}$)

Parameter	Symbol	Rating	Unit	
Input	Forward current	I_F	50	mA
	Reverse voltage	V_R	6	V
	Power dissipation	P	75	mW
Output	Collector-emitter voltage	V_{CEO}	35	V
	Emitter-collector voltage	V_{ECO}	6	V
	Collector current	I_C	20	mA
	Collector power dissipation	P_C	75	mW
Total power dissipation	P_{tot}	100	mW	
Operating temperature	T_{opr}	-25 to +85	$^\circ\text{C}$	
Storage temperature	T_{stg}	-40 to +100	$^\circ\text{C}$	
*1 Soldering temperature	T_{sol}	260	$^\circ\text{C}$	

*1 For 3s

■ Electro-optical Characteristics ($T_a=25^\circ\text{C}$)

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit		
Input	Forward voltage	V_F	$I_F=20\text{mA}$	-	1.2	1.4	V	
	Reverse current	I_R	$V_R=3\text{V}$	-	-	10	μA	
Output	Collector dark current	I_{CEO}	$V_{CE}=20\text{V}$	-	-	100	nA	
Transfer characteristics	Collector current	I_C	$V_{CE}=5\text{V}, I_F=5\text{mA}$	50	-	300	μA	
	Response time	Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_F=10\text{mA}, I_C=50\mu\text{A}$	-	-	0.4	V
		Rise time	t_r	$V_{CE}=5\text{V}, I_C=100\mu\text{A}, R_L=1\text{k}\Omega$	-	35	100	μs
	Fall time	t_f	-		35	100	μs	

Fig.1 Forward Current vs. Ambient Temperature

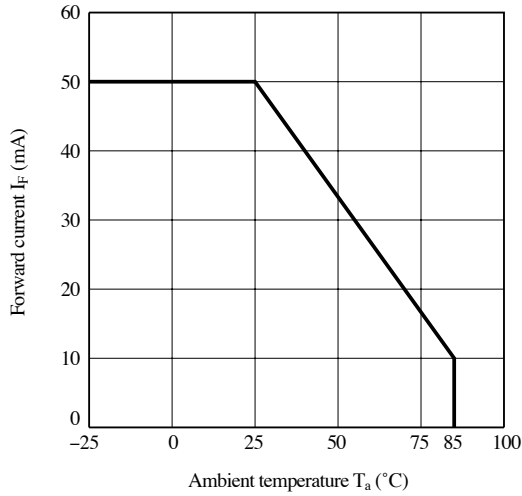


Fig.2 Power Dissipation vs. Ambient Temperature

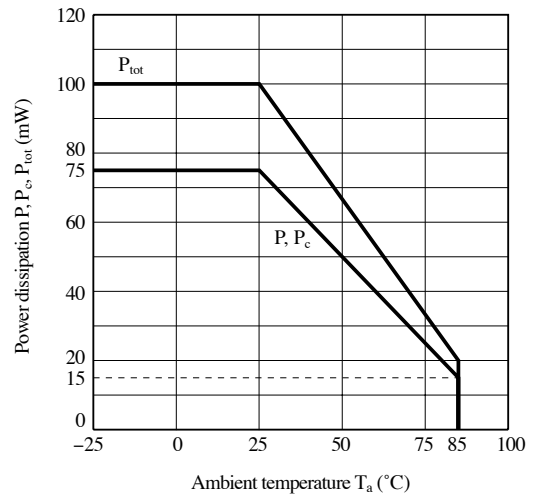


Fig.3 Forward Current vs. Forward Voltage

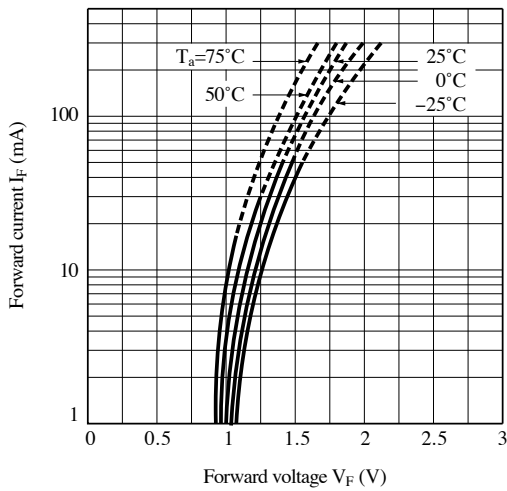


Fig.4 Collector Current vs. Forward Current

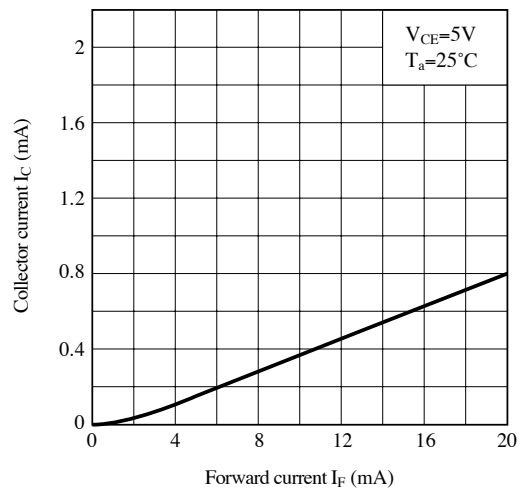


Fig.5 Collector Current vs. Collector-emitter Voltage

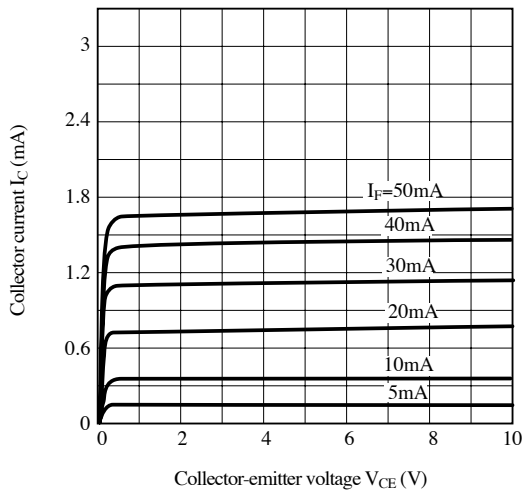


Fig.6 Relative Collector Current vs. Ambient Temperature

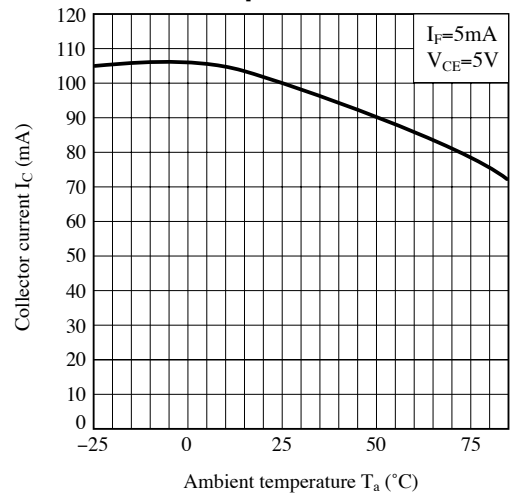


Fig.7 Collector-emitter Saturation Voltage vs. Ambient Temperature

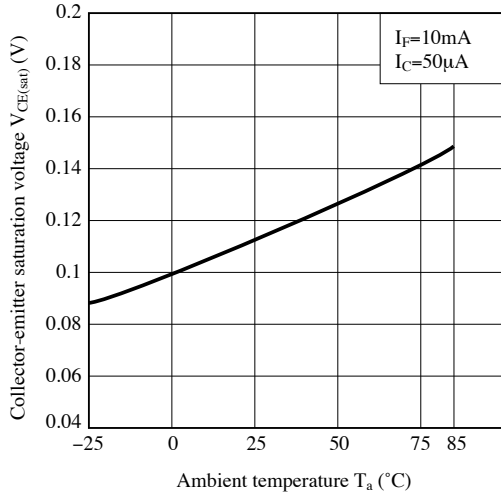


Fig.8 Dark Current vs. Ambient Temperature

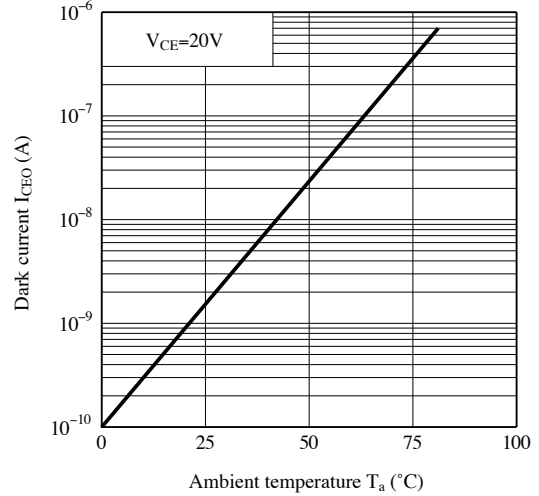


Fig.9 Response Time vs. Load Resistance

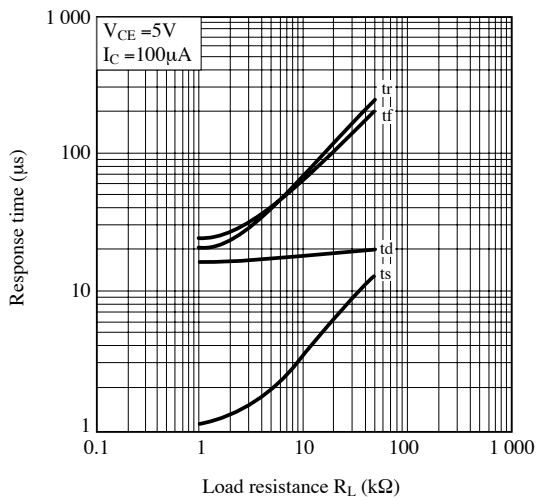


Fig.10 Test Circuit for Response Time

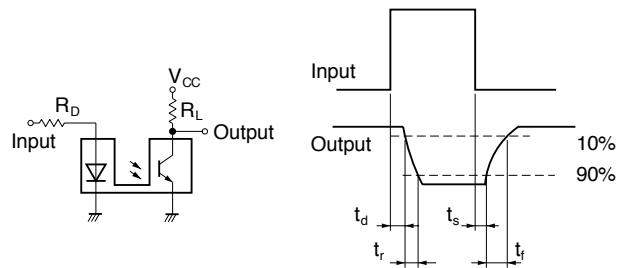


Fig.11 Detecting Position Characteristics (1)

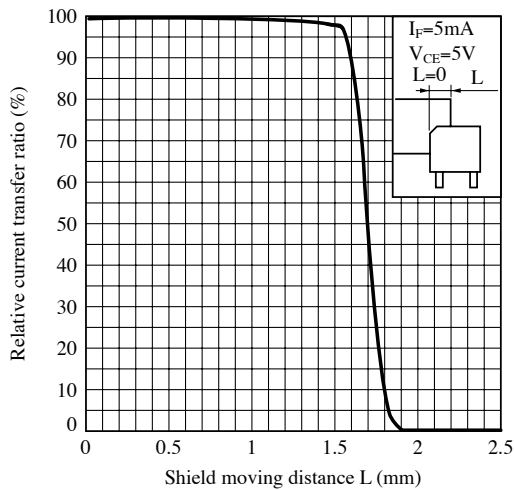
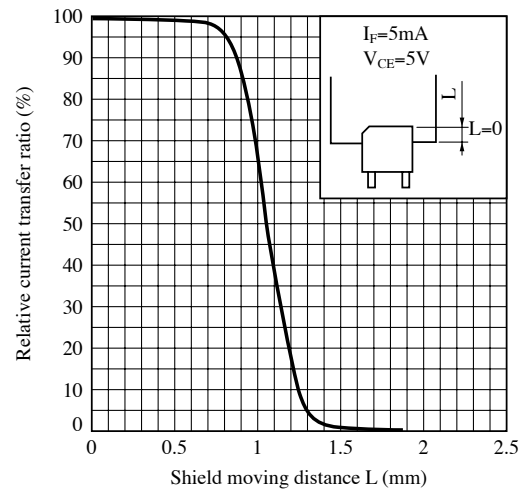


Fig.12 Detecting Position Characteristics (2)



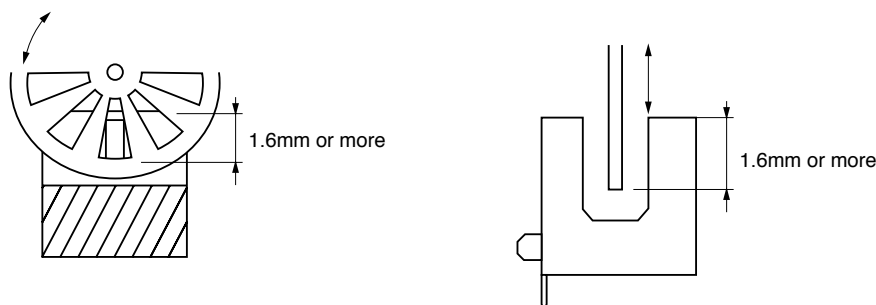
Remarks : Please be aware that all data in the graph are just for reference and not for guarantee.

■ Design Considerations

● Design guide

- 1) Prevention of detection error
To prevent photointerrupter from faulty operation caused by external light, do not set the detecting face to the external light.
- 2) Position of opaque board
Opaque board shall be installed at place 1.6mm or more from the top of elements.

(Example)



This product is not designed against irradiation and incorporates non-coherent IRED.

● Degradation

In general, the emission of the IRED used in photointerrupter will degrade over time.
In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

● Parts

This product is assembled using the below parts.

• Photodetector (qty. : 1)

Category	Material	Maximum Sensitivity wavelength (nm)	Sensitivity wavelength (nm)	Response time (μs)
Phototransistor	Silicon (Si)	930	700 to 1 200	20

• Photo emitter (qty. : 1)

Category	Material	Maximum light emitting wavelength (nm)	I/O Frequency (MHz)
Infrared emitting diode (non-coherent)	Gallium arsenide (GaAs)	950	0.3

• Material

Case	Lead frame
Black polyphernylene sulfide resin (UL94 V-0)	42Alloy

■ **Manufacturing Guidelines**

● **Storage and management after open**

Storage condition

Storage temp.: 5 to 30°C, Storage humidity : 70%RH or less at regular packaging.

Treatment after opening the moisture-proof package

After opening, you should mount the products while keeping them on the condition of 5 to 25°C and 70%RH or less in humidity within 4 days.

After opening the bag once even if the prolonged storage is necessary, you should mount the products within two weeks.

And when you store the rest of products you should put into a DRY BOX. Otherwise after the rest of products and silicagel are sealed up again, you should keep them under the condition of 5 to 30°C and 70%RH or less in humidity.

Baking before mounting

When the above-mentioned storage method could not be executed, please process the baking treatment before mounting the products.

However the baking treatment is permitted within one time.

Recommended condition : 125°C, 16 to 24 Hour

*Do not process the baking treatment with the product wrapped. When the baking treatment processing, you should move the products to a metallic tray or fix temporarily the products to substrate.

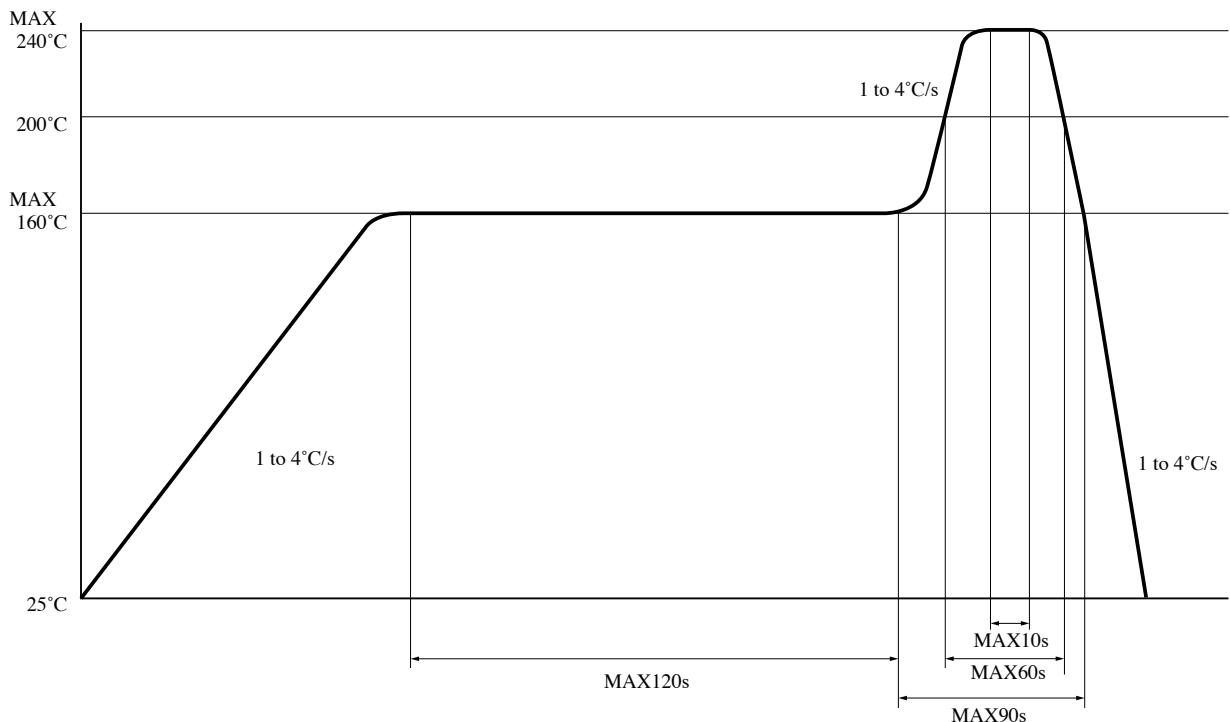
● **Soldering Method**

Reflow Soldering:

Reflow soldering should follow the temperature profile shown below.

Soldering should not exceed the curve of temperature profile and time.

Please solder within one time.



Hand soldering

Hand soldering should be completed within 3 s when the point of solder iron is below 350°C.

Please solder within one time.

Please don't touch the terminals directly by soldering iron.

Soldered product shall treat at normal temperature.

Other notice

Please take care not to let any external force exert on lead pins.

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the cooling and soldering conditions.

Note for installing

Please don't give force to lead. Because inner 2-leads in 4-leads are put in package by forming, they may come off by force.

Lead pin

Lead terminals of this product are tin copper alloy plated. Before usage, please evaluate solderability with actual conditions and confirm. And the uniformity in color for the lead terminals are not specified.

● Cleaning instructions

Solvent cleaning :

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

Ultrasonic cleaning :

Do not execute ultrasonic cleaning.

Recommended solvent materials :

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

● Presence of ODC

This product shall not contain the following materials.

And they are not used in the production process for this product.

Regulation substances : CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBB and PBDE are not used in this product at all.

This product shall not contain the following materials banned in the RoHS Directive (2002/95/EC).

•Lead, Mercury, Cadmium, Hexavalent chromium, Polybrominated biphenyls (PBB), Polybrominated diphenyl ethers (PBDE).

■ Package specification

● Sleeve package

Package materials

Sleeve : Polyphernylene

Stopper : Styrene-Elastomer

Aluminum laminated Bag : Nylon, Polyphernylene, Aluminum

Package method

MAX. 50 pcs. of products shall be packaged in a sleeve. Both ends shall be closed by tabbed and tabless stoppers.

MAX. 40 sleeves with silicagel are enclosed in aluminum laminated bag. After sealing up the bag, it encused in one case.

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- Telecommunication equipment [terminal]
- Test and measurement equipment
- Industrial control
- Audio visual equipment
- Consumer electronics

(ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection

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- Traffic signals
- Gas leakage sensor breakers
- Alarm equipment
- Various safety devices, etc.

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- Telecommunication equipment [trunk lines]
- Nuclear power control equipment
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